TOSHIBA INSULATED GATE BIPOLAR TRANSISTOR SILICON N CHANNEL TYPE

GT20D101

HIGH POWER AMPLIFIER APPLICATION

• High Breakdown Voltage : V_{CES}=250V (Min.)

• High Forward Transfer Admittance : $|Y_{fe}| = 10S (Typ.)$

• Complementary to GT20D201

• Enhancement-Mode

MAXIMUM RATINGS (Ta = 25°C)

CARACTERISTICS	SYMBOL	RATINGS	UNIT
Collector-Emitter Voltage	v_{CES}	250	V
Gate-Emitter Voltage	V_{GES}	±20	V
Collector Current	$I_{\mathbf{C}}$	20	A
Latch Up Current	$I_{ m L}$	60	A
Collector Power Dissipation (Tc=25°C)	PC	180	w
Junction Temperature	T_{j}	150	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~150	°C

Unit in mm

20.5MAX

93.3±0.2

1. GATE
2. COLLECTOR (HEAT SINK)
3. EMITTER

JEDEC

EIAJ

TOSHIBA

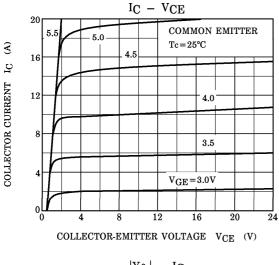
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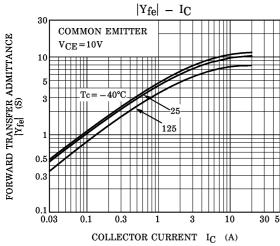
Weight: 9.75g

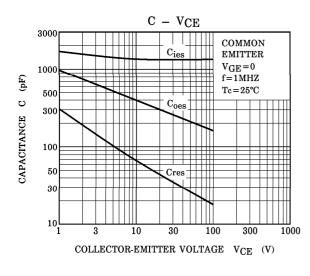
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

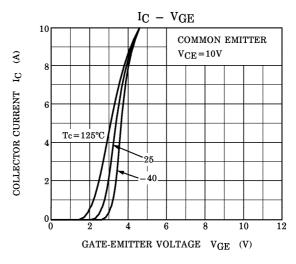
CARACTERISTICS	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICES	$V_{CE} = 250V, V_{GE} = 0$	_	_	50	μ A
Gate Leakage Current	$I_{ ext{GES}}$	$V_{GE} = \pm 20V, V_{CE} = 0$			±10	μ A
Collector-Emitter Saturation Voltage	V _{CE} (sat)	$I_{C} = 15A, V_{GE} = 10V$	_	1.5	3.0	V
Gate-Emitter Cut-off Voltage	V _{GE (OFF)}	$V_{CE} = 10V, I_{C} = 100mA$	1.4	_	3.2	V
Forward Transfer Admittance	Y _{fe}	$V_{\text{CE}} = 10V, I_{\text{C}} = 1A$	_	3	_	S
	Y _{fe}	$V_{\text{CE}} = 10V, I_{\text{C}} = 10A$	_	10	_	
Input Capacitance	$C_{ m ies}$	$V_{ m CE}\!=\!10{ m V},~I_{ m E}\!=\!0 \ { m f}\!=\!1{ m MHz}$	_	1400	_	pF
Output Capacitance	C _{oes}	$V_{ ext{CE}} = 10 ext{V}, \ ext{I}_{ ext{E}} = 0 \ ext{f} = 1 ext{MHz}$	_	400	_	pF
Reverse Transfer Capacitance	$\mathrm{C}_{\mathrm{res}}$	$V_{\text{CE}} = 10 \text{V}, \ I_{\text{E}} = 0 \\ f = 1 \text{MHz}$	_	65	_	pF

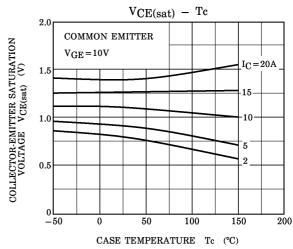
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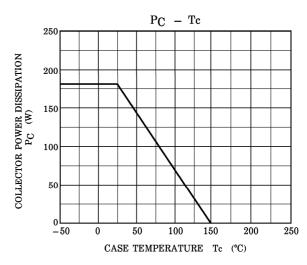




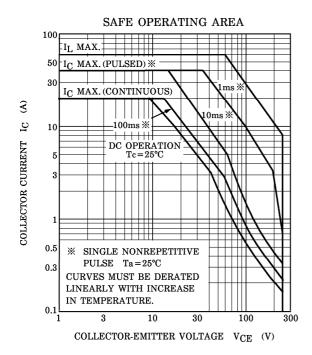








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